

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 103213-00098	SERIAL NO. New Application
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT KOBAYASHI et al	
		FILING DATE September 20, 2004	GROUP

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION		
							YES	NO	PART.
FKIII	AG	2002-55004	2/20/2002	Japan				xx	
FKIII	AH	2000-311563	11/7/2000	Japan				xx	
	AI								
	AJ								
	AK								
	AL								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AM	
	AN	
	AO	

EXAMINER /Freddie Kirkland III/	DATE CONSIDERED 12/09/2006
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Sheet 1 of 1

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

103213-00098

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SERIAL NO.

307367
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LIST OF REFERENCES CITED BY APPLICANT

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FILING DATE

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U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
FKIII	AA	6,109,113	8/29/2000	Chavan et al			
	AB						
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	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION		
							YES	NO	PART.
FKIII	AG	7-83776	3/31/1995	Japan				xx	
	AH								
	AI								
	AJ								
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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